

A3 Claim 12 (Amended): Apparatus according to claim 10, characterized in that the first and second coil devices (24, 31) are arranged fixedly in relation to each other and are preferably embedded in a casting composition.

A4 Claim 17 (Amended): Apparatus according to claim 15, characterized in that the probe head (14) is retractable into the protective sleeve (16) against a spring force, and in that a spring element (37) is arranged with at least slight biasing with respect to the guide sleeve (17).

A5 Claim 19 (Amended): Circuit for the separate evaluation of two measuring signals, in particular for carrying out the method according to claim 1, characterized in that the detuning of a respective inductance (24, 31) results in a change in frequency, on inductance (24) being influenced primarily by the layer thickness and the other inductance (31) being influenced primarily by the curvature of the object of measurement.